

CMOS BCD-to-Seven-Segment Latch/Decoder/Driver For Liquid-Crystal Displays

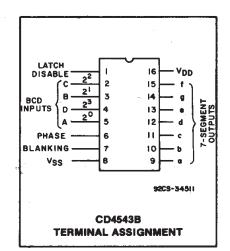
High-Voltage Types (20-Volt Rating)

Features:

- Display blanking of all illegal input combinations
- Latch storage of code
- Capability of driving two low power TTL loads, two HTL loads, or one low power Schottky load over the full rated-temperature range
- Pin-for-pin replacement for the CD4056B (with pin 7 tied to VSS)
- Direct LED driving capability

CD4543B is a BCD-to-seven segment latch/decoder/driver designed primarily for liquid-crystal display (LCD) applications. It is also capable of driving light emitting diode (LED), incandescent, gas-discharge, and fluorescent displays. This device is functionally similar to and serves as direct replacement for the CD4056B when pin 7 is connected to V_{SS} . It differs from the CD4056B in that it has a display blanking capability instead of a level-shifting function and requires only one power supply. When the CD4056B is used in the level shifting mode, two power supplies are required. When the CD4543B is used for LCD applications, a square wave must be applied to the PHASE input and the backplane of the LCD device. For LED applications a logic 1 is required at the PHASE input for common-cathode devices; a logic 0 is required for commonanode devices (see truth table).

The CD4543B is supplied in hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).



- 100% tested for guiescent current at 20 V
- Maximum input current of 1 µA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (full package-temperature range)= 1 V at V_{DD}=5 V

- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

- Instrument display driver
- Dashboard display driver
- Computer/calculator display driver
- Timing device driver (clocks, watches, timers)

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MAXIMUM P	RATINGS, Absolu	te-Maximum	n Values:						
	-VOLTAGE RANG								
Voltages r	eferenced to VSS	Ferminal)							-0.5V to +20V
INPUT VOLT	AGE RANGE, ALL	.INPUTS						0.5\	to V _{DD} +0.5V
DC INPUT C	URRENT, ANY ON	IE INPUT							±10mA
	SIPATION PER P								
For $T_A = -$	55°C to +100°C		• • • • • • • • • • • • • • • • • • •						500mW
For $T_A = +$	-100°C to +125°C						Derate L	inearity at 12mW	/ºC to 200mW
	SIPATION PER O			· ·					
FOR $T_A =$	FULL PACKAGE-	TEMPERAT	URE RANGE (All Pac	kage Types)					100mW
OPERATING	-TEMPERATURE	RANGE (TA)					55	0°C to +125°C
STORAGE T	EMPERATURE R/	ANGE (Tsta)						65	5°C to +150°C
LEAD TEMP	ERATÜRE (DURI	NG SOLDEF	RING):		•				
At distance	e 1/16 ± 1/32 incl	1.59 ± 0.7	9mm) from case for 1	0s max		• • • • • • • • •	• • • • • • • •	•••••••••••••••••••••••••••••••••••••••	+265°C

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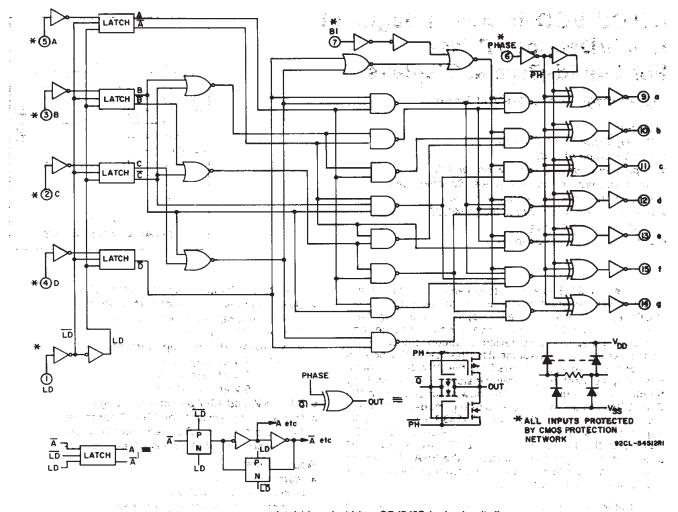


Fig. 1 – BCD-to-seven-segment latch/decoder/driver CD4543B logic circuit diagram.

RECOMMENDED OPERATING CONDITIONS at TA=25°C, Unless Otherwise Specified

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

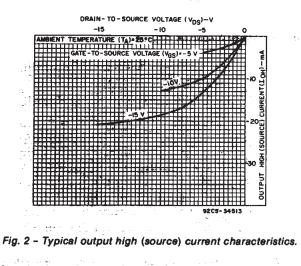
		LiN	I ITS 🗟 🖓 🖓	
CHARACTERISTIC	VDD (V)	MIN.	TYP.	UNITS
Supply-Voltage Range (For TA=Full Package-Temperature Range)		3	18	V
	5	250	125	1.1
Latch Disable Pulse Width twh	10.	100	50	
	15	80	40	
	5	60	15	
Minimum Data Setup Time tsu	10	20	-5	ns
	15	10	-5	
	5	25	-5]
Minimum Data Hold Time t _H	10	20	10	
	15	20	10	

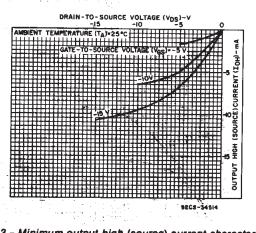
STATIC ELECTRICAL CHARACTERISTICS

CHARAC-	na an Inger Inger Provinsion Provinsion	со	NDITION	IS	Lin	NITS AT	INDICA	TED TEN	IPERAT	URES (°(C)	
TERISTIC	²	٧o	VIN	VDD				1		+25		UNITS
	100 A.A. 100 A.A.	(V)	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.	1
Quiescent		- 	0, 5	5	5	5	150	150	—	0.04	5	1
Device	n ng Galain An galain agus	<u>6.3</u> *	0,10	10	10	10	300	300	-	0.04	10	
Current	IDD	<u> </u>	0,15	15	20	20	600	600	—	0.04	20	μA
Max.		—	0,20	20	100	100	3000	3000		0.08	100	
Output Low (Sink)		0.4	0, 5	5	0.64	0.61	0.42	0.36	0.51	1	_	
Current	Lai	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	—	
Min.	IOL	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	-	
Output High		4.6	0, 5	5	-0.46	-0.44	-0.30	-0.26	-0.37	-0,75		mA
(Source)		2.5	0, 5	5	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6		1
Current	10H-	9.5	0,10	10	-0.98	-0.92	-0.68	-0.55	-0.8	-1.6	—	
Min.		13.5	0,15	15	-3.33	-3.18	-2.2	-1.9	-2.7	-5.4		
Output Voltage:	n The second second		0, 5	5		0.	05		—	0	0.05	
Low-Level	VOL	-	0,10	10		0.	05		—	0	0.05	
Max.			0,15	15		0.	05		—	0	0.05	v
Output Voltage:		. —	0, 5	5		4.9	95		4.95	5	—	. •
High-Level	Voн	-	0,10	. 10	tat in	9.9	95	8 î.	9.95	10	<u> </u>	the arrive of the second se
Min.		—	0,15	15		14.	95		14.95	15	—	
Input Low		0.5,4.5		5		1.	.5	· *;		_	1.5	
Voltage	VIL	1, 9	ž. —	- 10		3	3				3	
, Max.		1.5,13.5		15	-	4	1	1		—	4	
Input High		0.5,4.5	、 —	5		3.	5	2 -	3.5	_	—	V
Voltage	VIH	1, 9	·	10		. 7	,	•	7	_	—	
Min.		1.5,13.5	2 —	15		1	1		11	_	_	
Input Current Max.	^l in		0,18	18	±0.1	±0.1	±1	, ±1	- েল্ল	±10 ⁻⁵	±0.1	μA

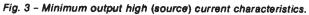


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DYNAMIC ELECTRICAL	CHARACTERISTICS &	t Ta=25° C:	CI =50 pF.	Input tr.tr=20 ns. F	ti =200 kΩ
		···A,		to the second set and second sec	

CHARACTERIST	ïC	TEST CONDITIONS		LIMITS All Packages			
		V _{DD} (V)	MIN.	TYP.	MAX.		
Propagation Delay Time	^t PHL	5	-	600	1200		
		10	—	200	400		
		15	-	150	300		
		5	-	500	1000		
	^t PLH	10	-	200	400		
		15		150	300		
		5		180	360	ç.	
Transition Time	THE	10	<u> </u>	90	180		
• •		15	·	65	130		
		5	. —	180	360	ns	
	ttlH	10	_	90	180		
		15		65	130		
		5	250	125	-		
Latch Disable Pulse Width	twн	10	100	50	-		
· · · ·		15	80	40	-		
		5	60	15	-		
Address Setup Time	tsu	10	20	-5			
·		15	10	-5	—		
		5	25	-5	-		
Address Hold Time	tH	10	20	10	_		
		15	20	10	· ·		
Input Capacitance	CIN	Any Input	-	5	7.5	pF	

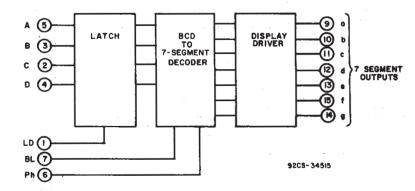
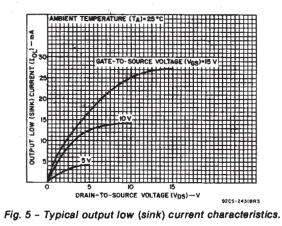
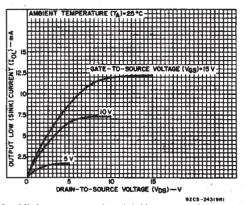
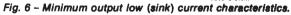


Fig. 4 - BCD-to-seven-segment latch/decoder/driver functional diagram.



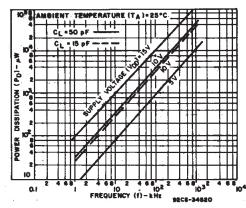




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· · · ·	TRITL	TABLE FOR	CD4543B
	- invin	TABLE FOR	0040400
	- N		

LD	INPUT CODE OUTPUT STATE													
	BI	Ph*	D	С	B			b	C	d	•	f	9	DISPLAY
X	1	0	x	x	X	X	0 -	Q	0		0	0	0	CHAR- ACTER
				_									0	0
1	0	0	0	0	0	E 0 .	1	1 1	1 1 6 1	1 0.	1 0	1	0	- <u></u>
1	0	0	0	0	1	0		1	0	1	1	0	1	2
1	0	0	0	0	1	1	1	1	1	1	0	0	1	5
1	0	0	0	se t e	- 0	0	0	1	. 1	Q	0	× 1	1	4
1	0	0	0	1	0	1 [.]	1	0	1	1	0	1	1	5
1	0	0	0	1	1	0		. 0	1	1	1	1	1	
1	0	0	0	1	1	1	1	1	1	0	0	0	0	E
, 1	.0	0	1	0	0	1	1 1:	1		1	0	1	1	 []
1	0	0		0	1	0	0	0	o	. 0	0	0	0	Blank
· 1 · ·	0	0	1 12	0	1	1	0	-0	0	10	0	0	0	Blank
1	<. 10-	0	1	1	0.,,	0	0	01	0	0	0	0	0	Blank
1	0	0	1	1	0	1	0	0	0	0	0	0	0	Blank
1	0	0	1	1	1	0	0	0	0	0	0	0	0	Blank
1	0	0	1	1	1	1	0	0	0	0	0	0	0	Blank
0	0	··· 0	X	. X	X	X			*					and the second
											Display as above			
V-D	't care				7	• •		4 Å.						
†≕Abo *≕For For	liquid-o commo commo	nbinatio crystal r on catho on anod pon the	eadout ode LEI e LED	D reado readou	outs, si ts, sele	iden Ph ct Ph=	n ≕0 . ∙1.							
†≕Abo *≕For For For	liquid-o commo commo	crystal r on catho on anod	eadout ode LEI e LED	D reado readou	outs, si ts, sele	iden Ph ct Ph=	n ≕0 . ∙1.							
†≕Abo *≕For For For	liquid-c commo commo ends`u	Tremperar		D readou readou code pr	BO	iden Ph ct Ph=	n ≕0 . ∙1.		PROPAGATION DELAY (IPHL, IPLH) IN			NTRE CONTRACTOR	60 (c))	
t=Abo *=For For **=Dep		T TEMPERAT		D reado readou code pr	eviousi evi	iner Ph- ct Ph- y appli			РВОРАКАТОН ОЕLAY (1 РНЦ. 1 РЦИ) — 11 20 - 20 - 20 - 20 - 20 - 20 - 20 - 20 -				60 (CL)-pF 92C3-	

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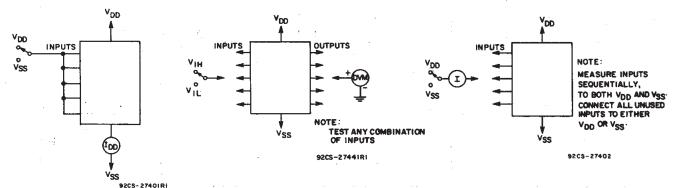


Fig. 11 - Input voltage test circuit.

Fig. 10 – Quiescent device current test circuit.

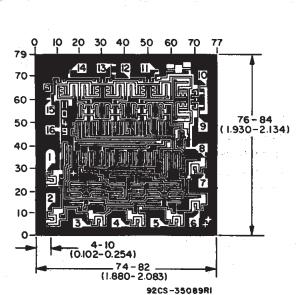


Fig. 12 - Input current test circuit.

Dimensions and pad layout for CD4543BH.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

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